MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PLED

AO4842-MS

Product specification





Description

The AO4842-MS uses advanced trench technology to provide excellent RDS(ON), low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

- VDS = 30V ID = 8.5A
- RDS(ON) < 19mΩ @ VGS=4.5V

Applications

- Battery protection
- Load switch
- Uninterruptible power supply

Reference News

PACKAGE OUTLINE	Dual N-Channel MOSFET	Marking
D1 D1 D1 SOP-8	D1 D1 D2 D2 80 70 60 50 10 20 30 40 S1 G1 S2 G2	MSKSEMI 4842 3SKJ**

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	
Vps	Drain-Source Voltage	30	V	
Vgs	Gate-Source Voltage	<u>+</u> 20	V	
lo@Ta=25°C	Drain Current, V _{GS} @ 4.5V ³	8.5	А	
lo@Ta=70°C	Drain Current, V _{GS} @ 4.5V ³	5.8	А	
Ірм	Pulsed Drain Current ¹	37	А	
PD@TA=25°C	Total Power Dissipation	1.5	W	
Тѕтс	Storage Temperature Range	-55 to 150	$^{\circ}$	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
Rthj-a	Maximum Thermal Resistance, Junction- ambient ³	85	°C/W	



Electrical Characteristics (T_J=25℃, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V	
△BV _{DSS} /△T _J	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.034		V/°C	
В	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =7A		17	19	0	
R _{DS(ON)}		V _{GS} =4.5V , I _D =4A		22	28	mΩ	
V _{GS(th)}	Gate Threshold Voltage	\/ -\/ -250A	1.2		2.5	V	
△V _{GS(th)}	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		-5.8		mV/°C	
	Drain Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =25°C			1		
I _{DSS}	Drain-Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =55°C			5	uA	
Igss	Gate-Source Leakage Current	$V_{GS} = \pm 20V$, $V_{DS} = 0V$			±100	nA	
gfs	Forward Transconductance	V _{DS} =5V , I _D =7A		6		S	
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2.5		Ω	
Qg	Total Gate Charge (4.5V)			6			
Q _{gs}	Gate-Source Charge	V _{DS} =15V , V _{GS} =4.5V , I _D =7A		2.5		nC	
Q _{gd}	Gate-Drain Charge			2.1			
T _{d(on)}	Turn-On Delay Time			2.4			
Tr	Rise Time	V_{DD} =15V , V_{GS} =10V , R_{G} =3.3 Ω		7.8			
T _{d(off)}	Turn-Off Delay Time	I _D =7A		22		ns	
Tf	Fall Time			4]	
C _{iss}	Input Capacitance			572			
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		80		pF	
Crss	Reverse Transfer Capacitance			65			

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
l s	Continuous Source Current ^{1,5}	\/ -\/ -0\/			7.3	Α
Іѕм	Pulsed Source Current ^{2,5}	V _G =V _D =0V , Force Current			37	Α
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V
t _{rr}	Reverse Recovery Time			20		nS
Qrr	Reverse Recovery Charge	lF=7A,dl/dt=100A/µs, TJ=25°C		1.1		nC

Note

- 1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%
- 3.The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH,I_{AS}=21A
- 4.The power dissipation is limited by 150°C junction temperature
- 5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

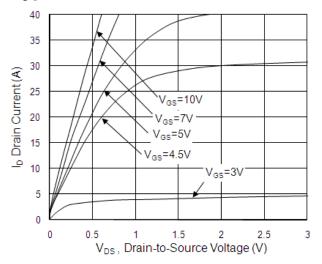


Fig.1 Typical Output Characteristics

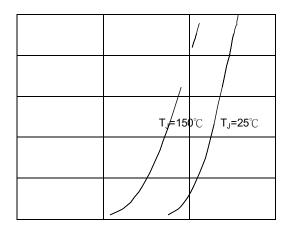


Fig.3 Forward Characteristics Of Reverse

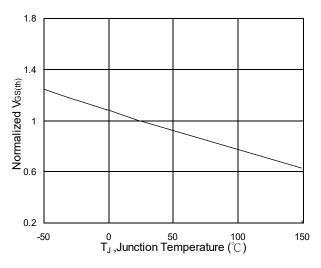


Fig.5 Normalized $V_{\text{GS(th)}}$ vs. T_{J}

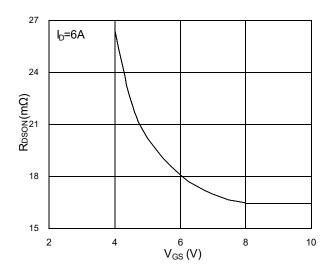


Fig.2 On-Resistance vs. G-S Voltage

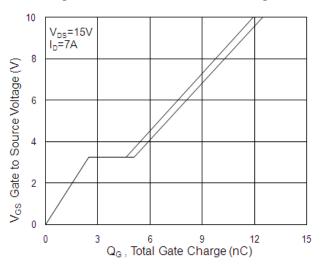


Fig.4 Gate-Charge Characteristics

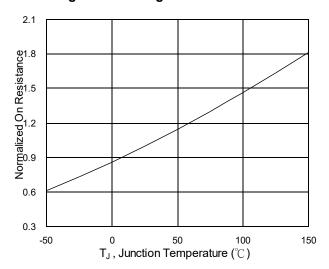
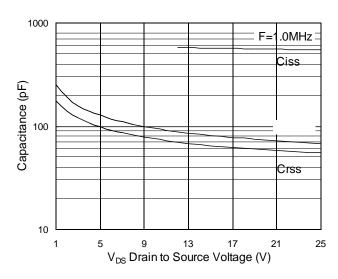


Fig.6 Normalized R_{DSON} vs. T_J





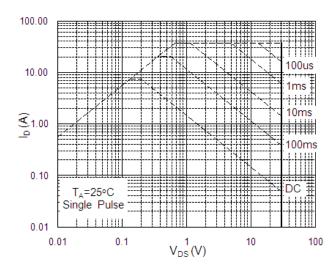


Fig.7 Capacitance

Fig.8 Safe Operating Area

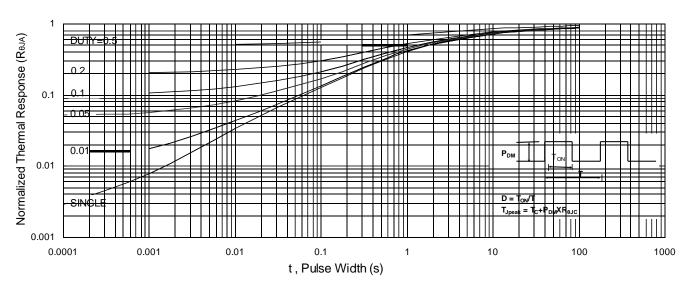


Fig.9 Normalized Maximum Transient Thermal Impedance

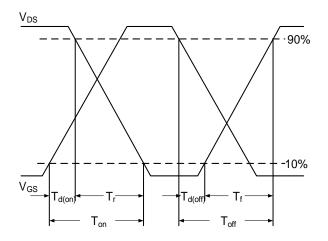


Fig.10 Switching Time Waveform

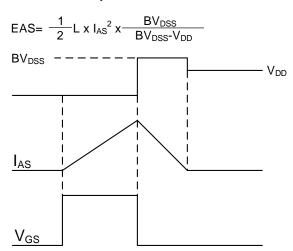
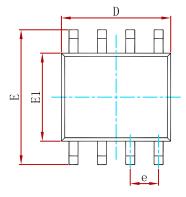
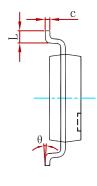


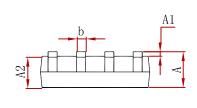
Fig.11 Unclamped Inductive Switching Waveform



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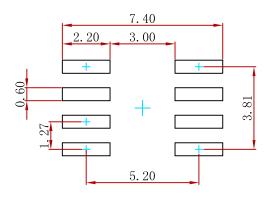






Cumbal	DimensionsInMillimeters		DimensionsInInches		
Symbol	Min	Max	Min	Max	
A	1.350	1. 750	0.053	0.069	
A1	0.100	0. 250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
c	0.170	0. 250	0.007	0.010	
D	4.800	5. 000	0. 189	0. 197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6. 200	0. 228	0. 244	
E1	3.800	4. 000	0. 150	0. 157	
L	0.400	1. 270	0.016	0.050	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
AO4842-MS	SOP-8	3000



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